



SEMI®  
International  
Standards

**TEST METHODS**  
**INTERNATIONAL TASK FORCE**  
**Monday, July 8, 2019**  
**11:00 AM – 12:00 PM**  
**Moscone Center, San Francisco, CA, USA**

## **AGENDA**

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1. Introductions
  - Anti-trust Reminder
  - Patentable Technologies Guidelines
  - International Effective Meeting Guidelines
2. Introductions and Agenda Review
3. Activities at SEMI Europa and SEMI Japan
4. Ballot Review
  - 4.1 No Ballots to consider
5. Old Business
  - 5.1 Documents for 5-year review
6. New Business
  - 6.1 Presentations
    1. Carrier Profiling of Semiconductors by Scanning Capacitance Microscopy and Scanning Spreading Resistance Microscopy  
By Mark J. Hagmann, NewPath Research
    2. Electrical Scanning Probe Microscopies for the Characterization of Advanced Nodes Nano Electronics  
By Umberto Celano, IMEC and Jay Mody, GlobalFoundries
  - 6.2 Plan for New Activity – SNARF
7. Action Item Review / Recommendations
8. Next Task Force Meeting
  - 8.1 SEMI N.A. 2020 Spring Mtg. March 30, 2020  
SEMI Headquarters, Milpitas, CA, USA  
Check [www.semi.org](http://www.semi.org) for the schedule
9. Adjourn